

## **Improved Edge Performance in Magnetorheological Finishing (MRF)**

*presented to:*

**Technology Days in the Government  
Mirror Development and Related  
Technologies**

**Huntsville, Alabama USA**

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**Acknowledgements:**

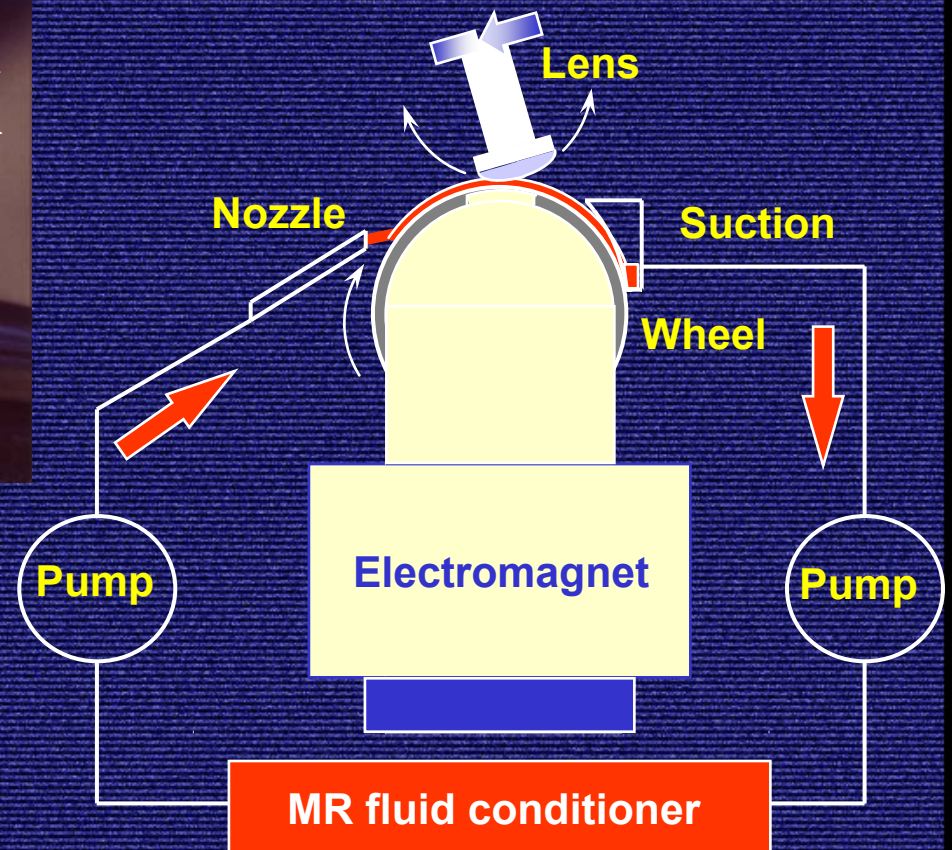
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**Dr. Philip Stahl**

**NASA SBIR 03-S2.05-7100**



# MRF – How it works





# MRF – Breakthrough Technology



## The MRF polishing tool:

- never dulls or changes
- is interferometrically characterized
- is easily adjusted
- conforms to part shape - works on complex shapes (flat, sphere, asphere, cylinder...)
- has high removal rates
- removal based on shear stress so applies very low normal load on abrasive, improving surface integrity
- **determinism leads to high convergence rate**
- **These attributes lead to a production oriented, deterministic, computer controlled polishing and figuring technique.**
- **Production proven: more than 90 machines worldwide**



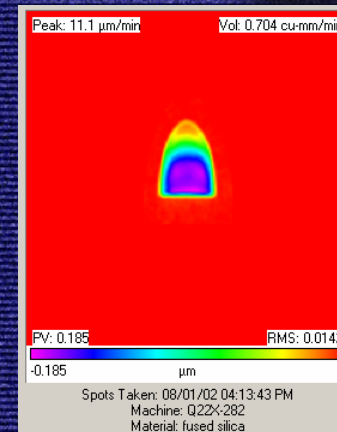
# Removal rate and roughness

## ❖ Removal rate dependent on:

- ❖ Material: FS, ULE, Zerodur, Si, SiC...
- ❖ Process parameters
- ❖ Machine/wheel size

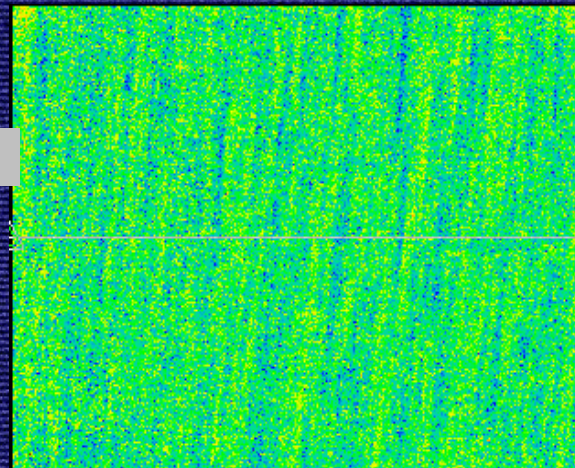
## ❖ Roughness

- ❖ MRF *smoothes* most materials
- ❖ E.g. fused silica results:

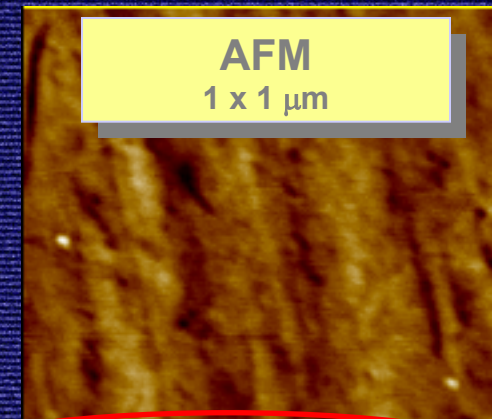


High Pass Filter (FTT Fixed – 12.5 1/mm)

Rmax	44.692	$\text{\AA}$
Ra	2.829	$\text{\AA}$
Rq	3.575	$\text{\AA}$



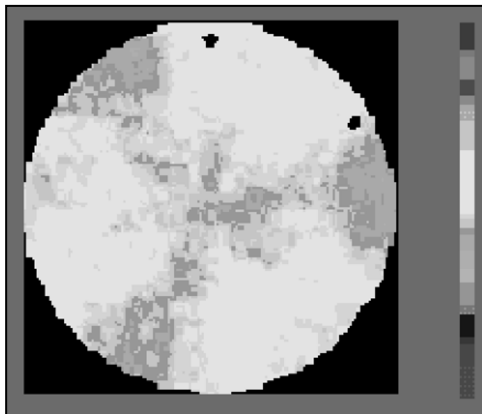
New-View 5000  
359 x 270  $\mu\text{m}$



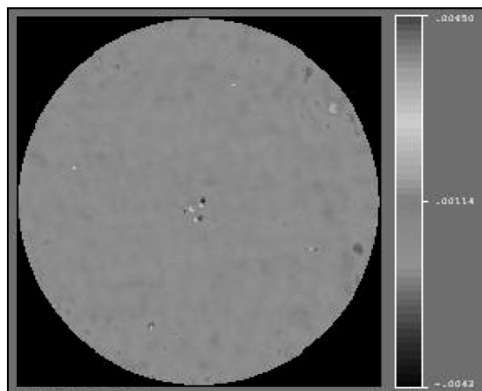
Img. Rms (Rq) 0.176 nm  
Img. Ra 0.136 nm  
Img. Rmax 1.884 nm



# Example of MRF Capability: CaF<sub>2</sub> Lenses for use in 157nm Lithography



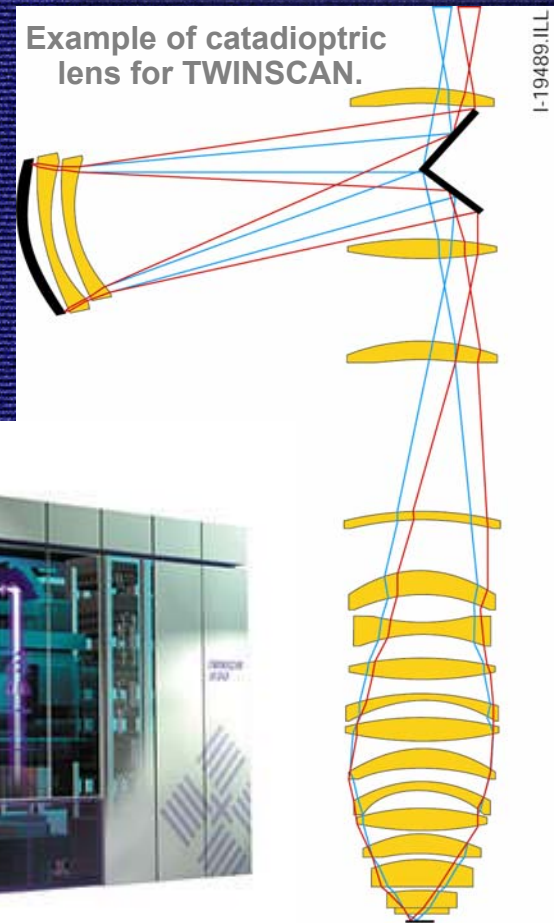
**<111> Element**  
**Surface figure: 0.57nm rms**



**<100> Element**  
**Surface figure: 0.63nm rms**



Example of catadioptric lens for TWINSCAN.

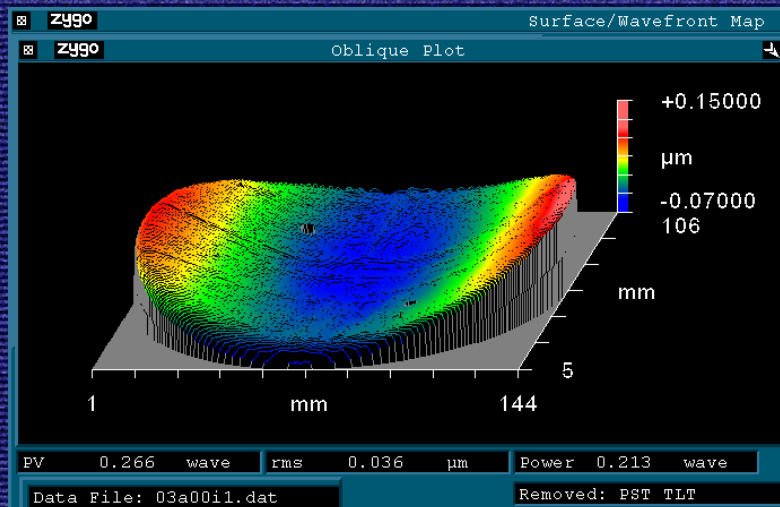


Jan Mulken (ASML), et al., "Optical lithography solutions for sub-65 nm semiconductor devices", Proc. of SPIE, 5040; pp: 753-762, 2003.



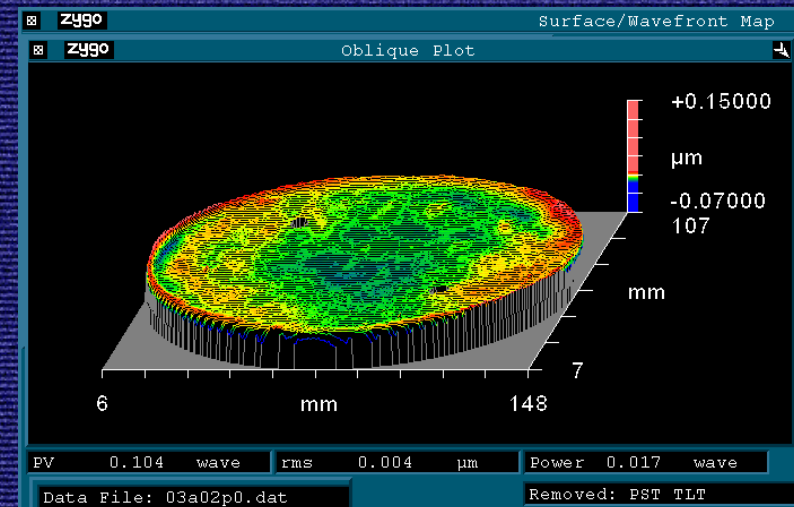
# Edge Effects - 6"x4" Elliptical Mirror Raster Polished

❖ MRF has demonstrated the ability to achieve very good results over part full aperture



PV = 0.27 λ  
RMS = 36.4 nm

47.26 min



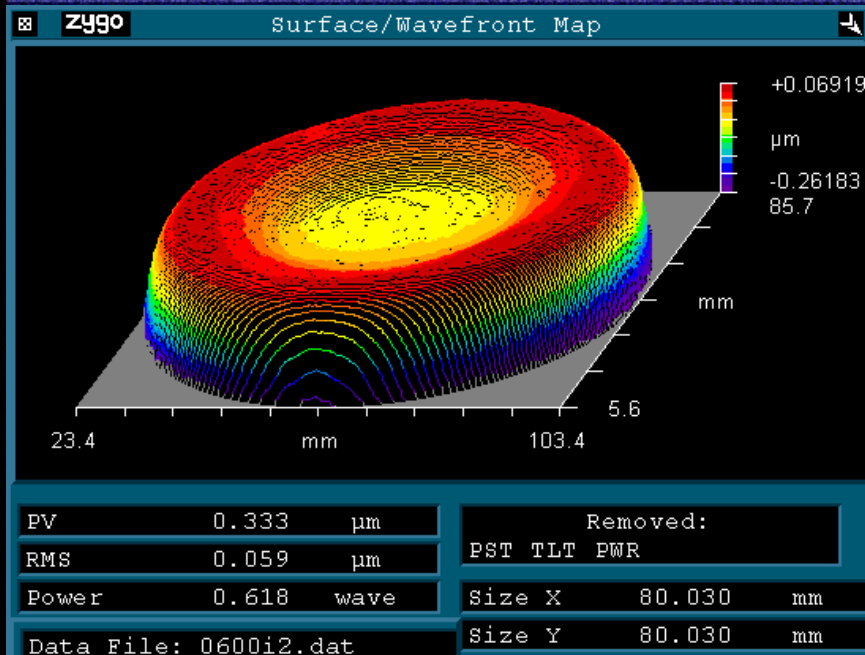
PV = 0.104 λ  
RMS = 4.1 nm

*Full Visible Aperture (i.e. no edge exclusion)*

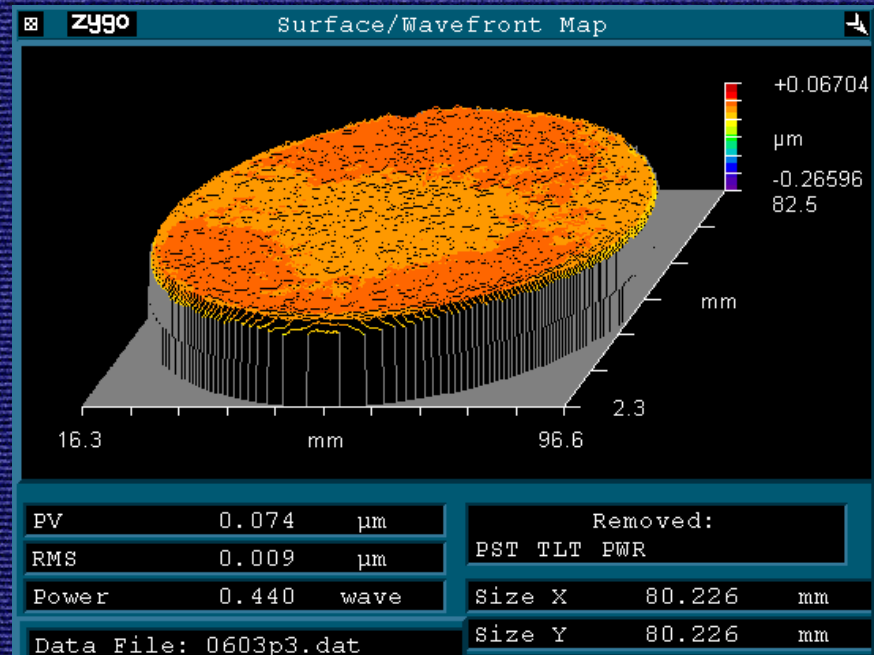


# 80 mm Diameter 148.331mm radius concave sphere

**Initial**



**Final**



**PV = 333 nm**

**RMS = 59 nm**

**185 min**

**PV = 74 nm**

**RMS = 9 nm**

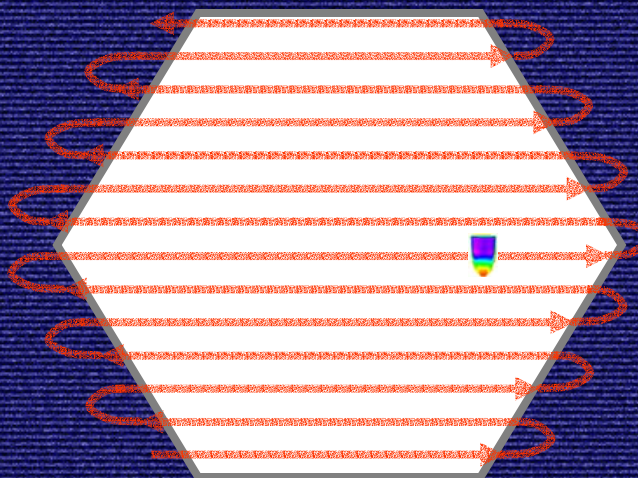
**Full Visible Aperture (i.e. no edge exclusion)**



# Fabricating Large Optics using MRF



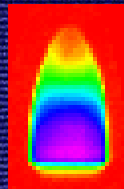
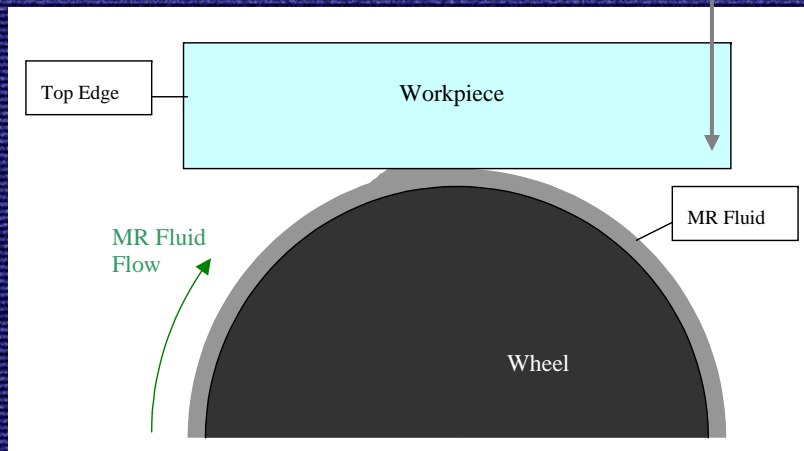
- ❖ Large *segmented* mirrors must have little or no edge exclusion
- ❖ Standard MRF has demonstrated good performance at edges for a variety of aperture sizes and shapes
- ❖ Work reported is to improve edges even further
- ❖ The primary goal is to understand process differences at the edge and develop an approach to account for them



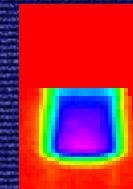
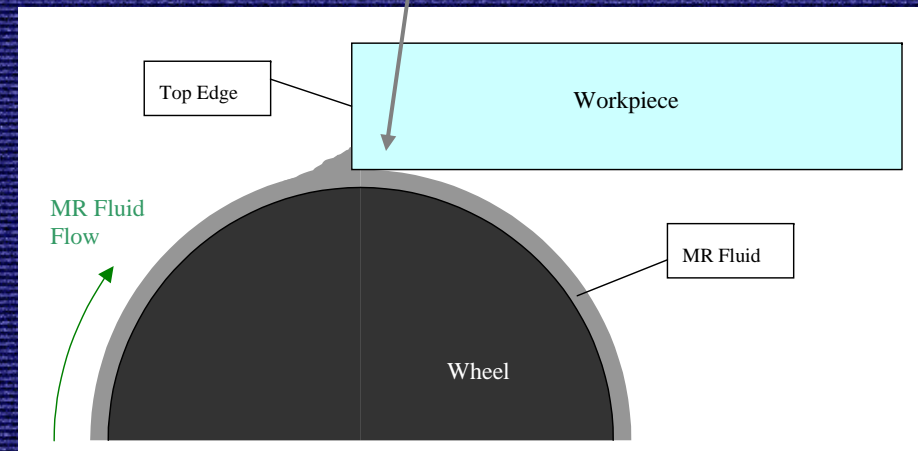


# Causes of Edge Effects

- ❖ MR fluid flow over edges differs from flow over surface, leading to changes in the tool removal function (“spot”)
- ❖ Edge performance at trailing edge, superior to leading edge due to flow characteristics



**Polishing away from edges**



**Polishing at edge**



# Methods of Eliminating Edge Effects

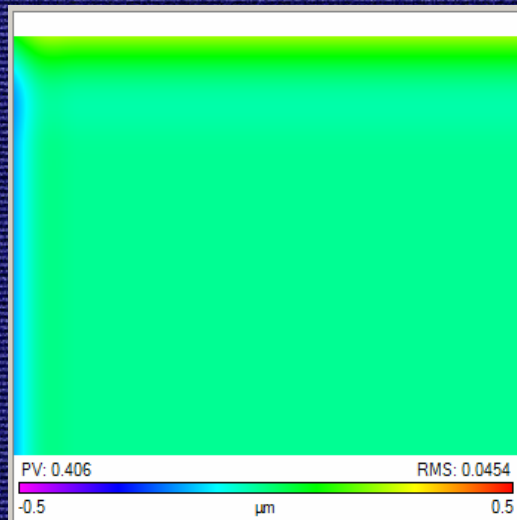


- ❖ **Edge extension: extend the workpiece surface with sacrificial hardware to eliminate the edges**
  - ❖ Usually impractical – extension height and slope must match workpiece exactly
  - ❖ Some benefit, but not pursued for above reasons
- ❖ **Variable plunge depth: use a smaller spot near edges**
  - ❖ Difficult to implement in software, but should provide best results
  - ❖ Planned Phase II activity
- ❖ **Edge spot characterization: model spot changes near edges and adjust dwell schedule**
  - ❖ More difficult to implement, results expected to be similar to variable plunge depth
- ❖ **Removal map modification: leave edge regions intentionally “high,” and correct with smaller spot**
  - ❖ Simplest to implement, but requires additional iteration

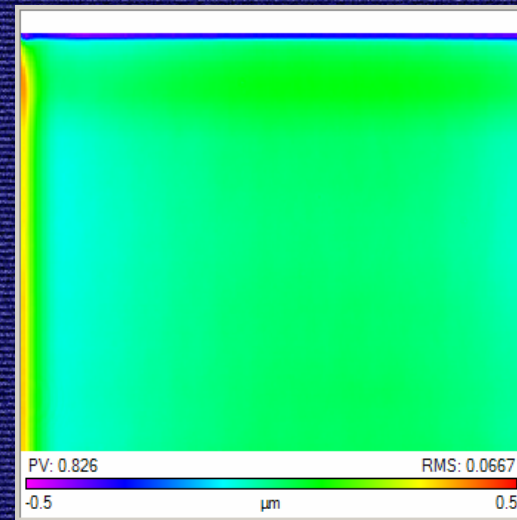


## Edge Spot Characterization

- ❖ Predict the variation of the spot at edges, and adjust the dwell schedule to compensate
- ❖ Spot variation at edges is complex and difficult to predict
- ❖ Prediction significantly different from actual, so method is not sufficient
- ❖ Work on this approach stopped for now



**Predicted removal map**



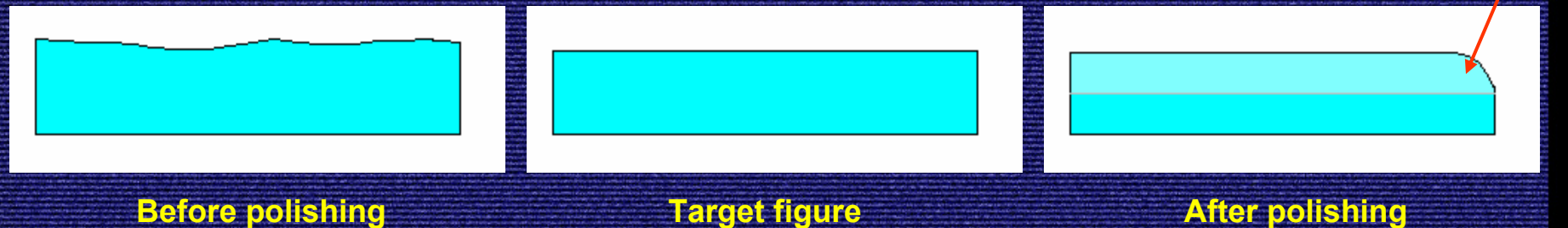
**Actual removal map**



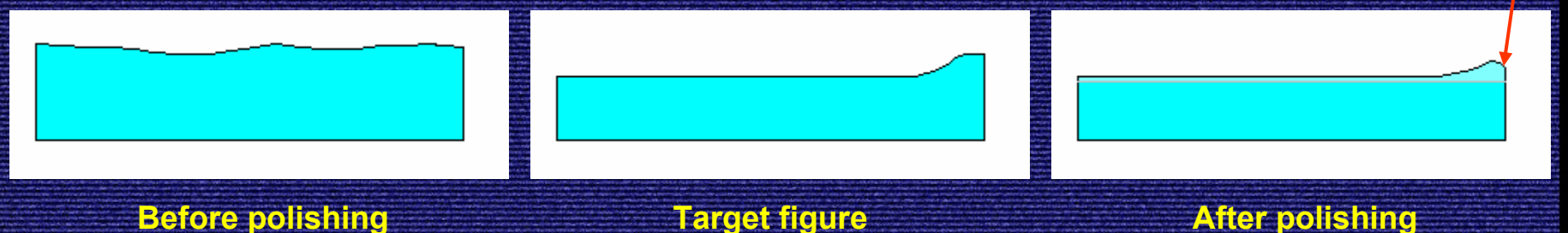
# Removal Map Modification

- ❖ **Where rolled edges are anticipated, remove less material so that edge regions are intentionally left “high”**
  - ❖ Minimizes amount of material that needs to be removed in second run
- ❖ **Correct edge regions with a smaller spot with subsequent iteration**

Without edge effects compensation:

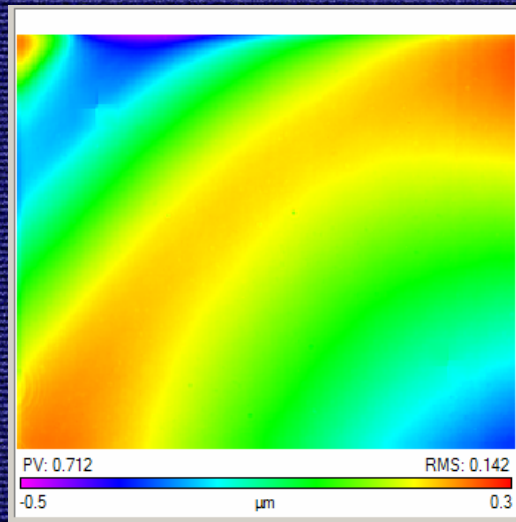


With edge effects compensation:

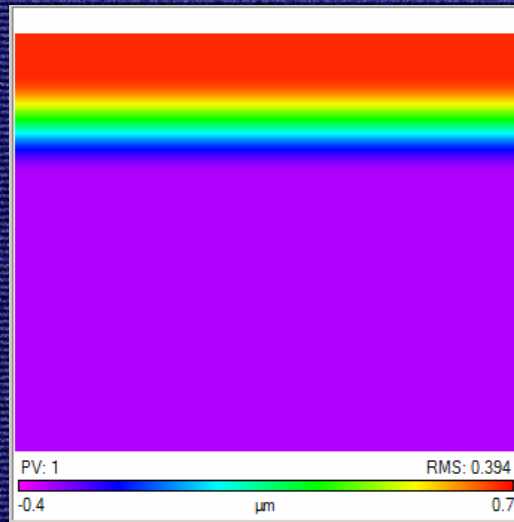




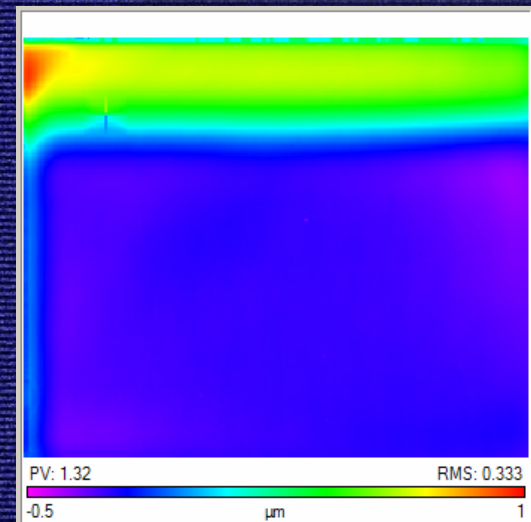
# Removal Map Modification



Initial figure map



Target figure map



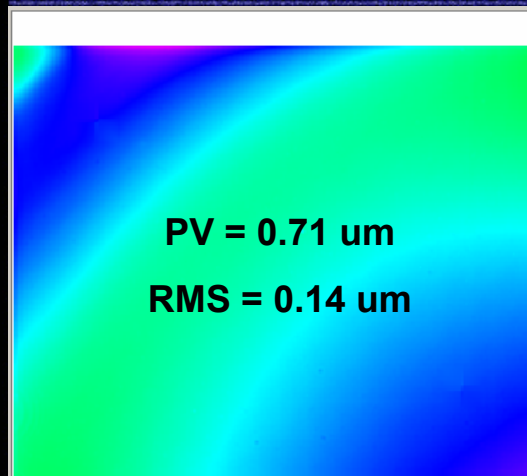
Result figure map

- ❖ Choose amplitude, extent, and profile of target figure map edge adjustment to minimize polishing time
- ❖ Subsequent polishing runs then performed to correct the “high” edge

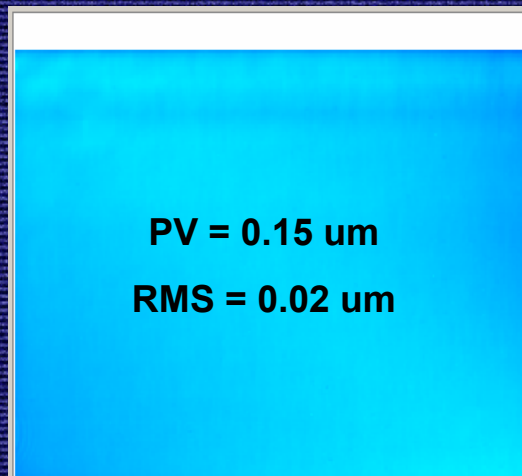
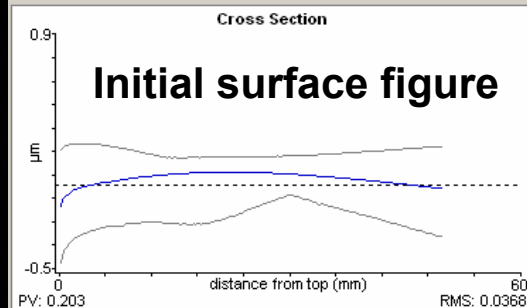


# Results to Date

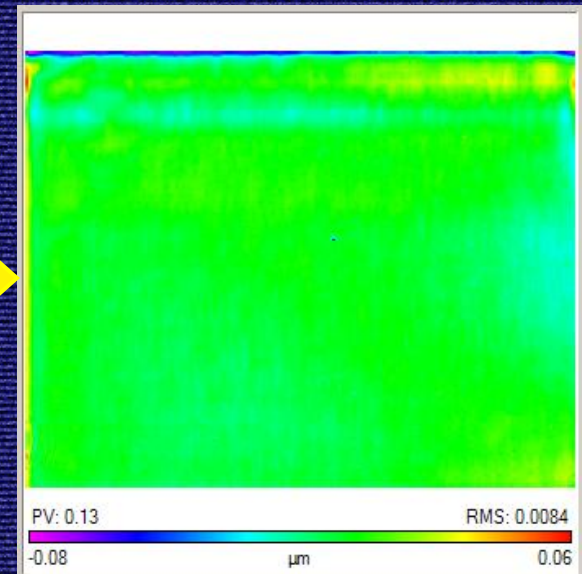
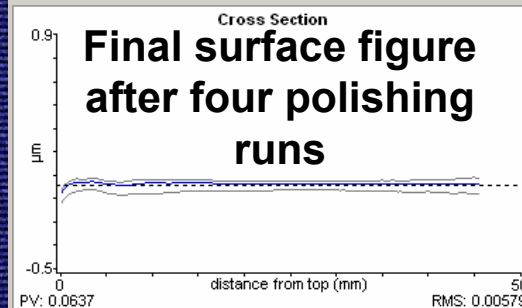
- ❖ After additional runs, small edge effect remains, but magnitude decreased by > 6x
- ❖ Within 2mm of edge



PV: 0.712 RMS: 0.142  
-0.5  $\mu\text{m}$  0.9



PV: 0.15 RMS: 0.0184  
-0.5  $\mu\text{m}$  0.9



PV: 0.13 RMS: 0.0084  
-0.08  $\mu\text{m}$  0.06

- ❖ Final surface on finer scale
- ❖ Some edge effect remains
- ❖ ~6x improvement compared with "standard" MRF



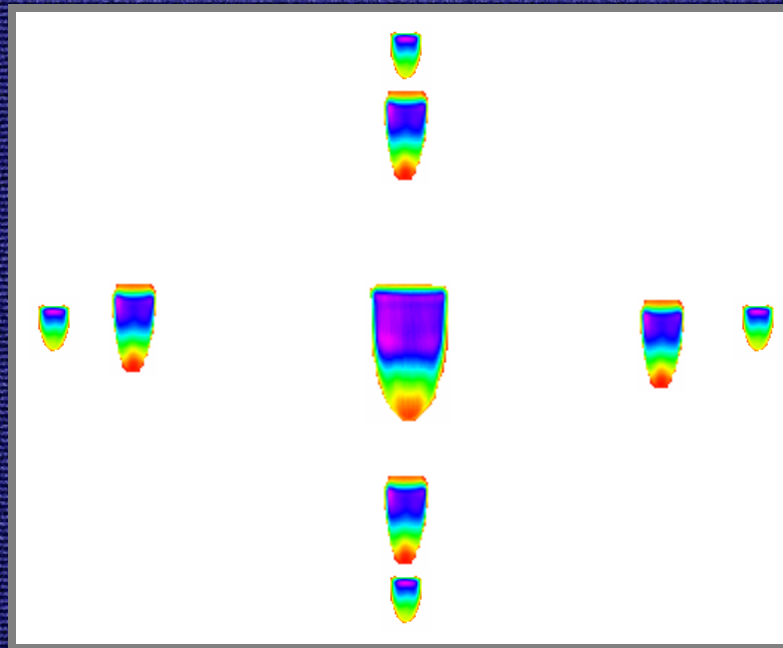
# Summary/Future Strategies

- ❖ **Edge effects in MRF are caused by flow interruption at edge**
- ❖ **Situation is well understood**
- ❖ **Several approaches have been identified to improve performance**
- ❖ **“Edge Extension” approach is impractical**
- ❖ **Limited success with “Edge Spot Characterization” approach**
- ❖ **Significant improvement with “Removal Map Modification”**
  - ❖ Additional work would improve efficiency of this approach by choosing more appropriate magnitude, extent and profile of edge
- ❖ **Develop variable plunge depth process**
  - ❖ Several ways to implement this, but more complex task
  - ❖ Should allow polishing closer to the edge with fewer iterations

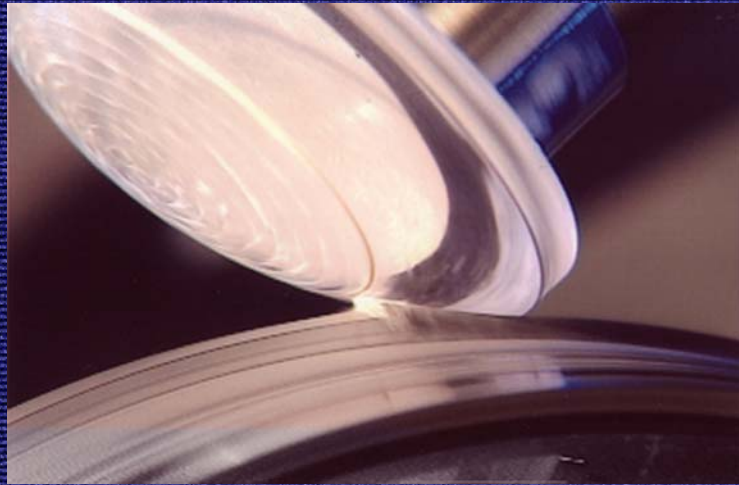


## Variable Plunge Depth

- ❖ Extent of edge effect is proportional to spot size
- ❖ Use larger spot (higher plunge depth) away from edges to remove material quickly; gradually make spot smaller (lower plunge depth) when approaching edges
- ❖ Technically feasible approach







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